

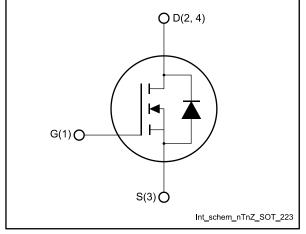
STN1NK60ZL

Datasheet - production data

N-channel 600 V, 10.4 Ω typ., 0.44 A SuperMESH™ Power MOSFET in a SOT-223 package

4 2 3 SOT-223

Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	ID	Ртот
STN1NK60ZL	600 V	15 Ω	0.44 A	3.3 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- ESD improved capability

Applications

• Switching applications

Description

This high voltage device is an N-channel Power MOSFET developed using the SuperMESH[™] technology by STMicroelectronics, an optimization of the well-established PowerMESH[™]. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

Table 1: Device summary

Order code	Marking	Package	Packing	
STN1NK60ZL	1NK60ZL	SOT-223	Tube	

This is information on a product in full production.

Contents

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1 Electrical ratings

 Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vds	Drain-source voltage	600	V
V _{GS}	Gate-source voltage	±20	V
ID	Drain current (continuous) at T _{amb} = 25 °C	0.44	А
lo	Drain current (continuous) at T _{amb} = 100 °C	0.3	А
IDM ⁽¹⁾	Drain current (pulsed)	1.8	А
Ртот	Total dissipation at T _{amb} = 25 °C	3.3	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	3	V/ns
Tj	Operating junction temperature range	- 55 to 150	°C
T _{stg}	Storage temperature range	- 55 10 150	C

Notes:

⁽¹⁾Pulse width limited by safe operating area.

 $^{(2)}I_{SD} \leq 0.3$ A, di/dt ≤ 200 A/µs, V_DD = 80%V_{(BR)DSS}

Table 3: Thermal data

Symbol	Parameter	Value	Unit
Rthj-amb ⁽¹⁾	Thermal resistance junction- ambient max	38	°C/W

Notes:

 $^{(1)}$ When mounted on 1 inch² FR-4 board, 2 Oz Cu, t < 3 s

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
lar	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax})$	0.3	А
Eas	Single pulse avalanche energy (starting Tj = 25 °C, $I_D = I_{AR}, V_{DD} = 50$ V)	150	mJ



2 Electrical characteristics

 T_C = 25 °C unless otherwise specified

Table 5: On/off-state						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	600			V
	7	$V_{GS} = 0 V, V_{DS} = 600 V$			1	μA
I _{DSS} Zero gate voltage drain current	$V_{GS} = 0 V, V_{DS} = 600 V$ $T_{C} = 125 \ ^{\circ}C^{(1)}$			50	μA	
lgss	Gate body leakage current	$V_{DS} = 0 V$, $V_{GS} = \pm 20 V$			±100	nA
VGS(th)	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50 \ \mu A$	0.9	1.7	2	V
R _{DS(on)}	Static drain-source on- resistance	V_{GS} = 10 V, I_D = 0.25 A		10.4	15	Ω

Notes:

⁽¹⁾Defined by design, not subject to production test.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	125	-	pF
Coss	Output capacitance	utput capacitance $V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz$		13	-	pF
Crss	Reverse transfer capacitance		-	2	-	pF
Qg	Total gate charge $V_{DD} = 480 \text{ V}, I_D = 0.8 \text{ A}$		-	9.4	-	nC
Qgs	Gate-source charge	V _{GS} = 10 V	-	0.8	-	nC
Q _{gd}	Gate-drain charge	(see Figure 15: "Test circuit for gate charge behavior")	-	4.5	-	nC

Table 6: Dynamic

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V_{DD} = 300 V, I _D = 0.4 A,	-	4.4	-	ns
tr	Rise time	$R_G = 4.7 \Omega$	-	4	-	ns
t _{d(off)}	Turn-off delay time	V _{GS} = 10 V (see <i>Figure 14: "Test circuit</i>	-	18.4	-	ns
t _f	Fall time	for resistive load switching times" and Figure 19: "Switching time waveform")	-	41	-	ns



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Electrical characteristics

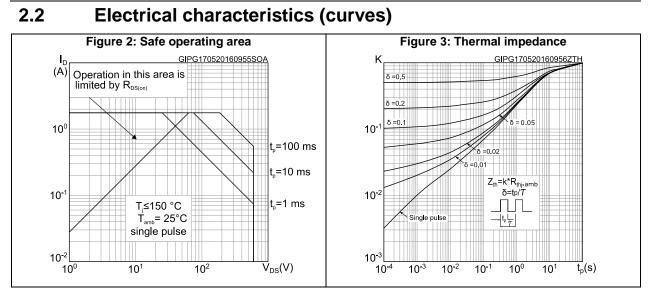
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Isd	Source-drain current		-		0.44	А
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		1.8	А
V _{SD} ⁽²⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 0.44 A	-		1.5	V
t _{rr}	Reverse recovery time	$I_{SD} = 0.8 \text{ A},$	-	155		ns
Qrr	Reverse recovery charge	di/dt = 100 A/ μ s,V _{DD} = 60 V (see <i>Figure 16: "Test circuit</i>	-	232		nC
Irrm	Reverse recovery current	for inductive load switching and diode recovery times")	-	3		А
trr	Reverse recovery time	I _{SD} = 0.8 A, di/dt = 100 A/µs	-	186		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, \text{ T}_{j} = 150 ^{\circ}\text{C}$ (see <i>Figure 16: "Test circuit</i>	-	297		nC
Irrm	Reverse recovery current	for inductive load switching and diode recovery times")	-	3.2		А

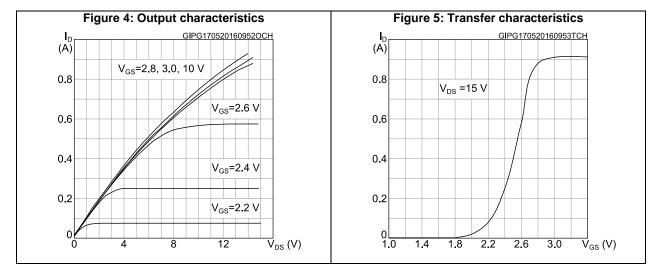
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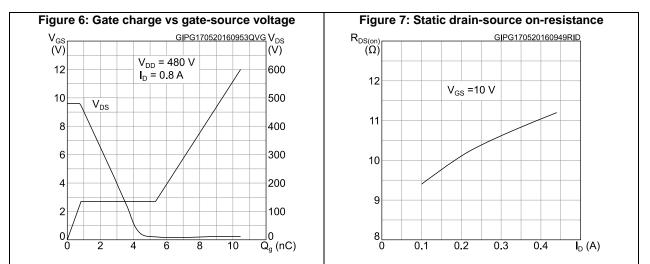
 $\ensuremath{^{(1)}}\ensuremath{\mathsf{Pulse}}$ width limited by safe operating area

 $^{(2)}\text{Pulsed:}$ pulse duration = 300 $\mu\text{s},$ duty cycle 1.5%









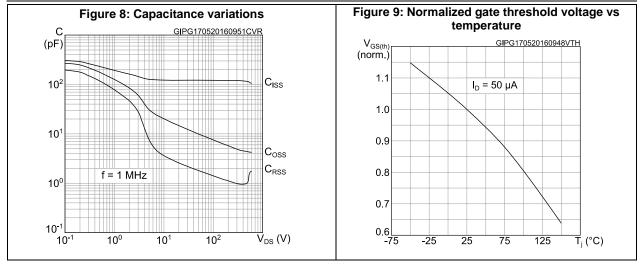
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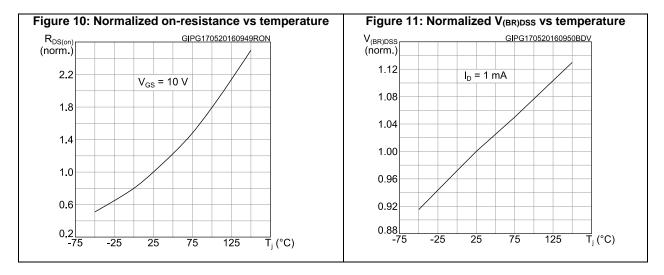


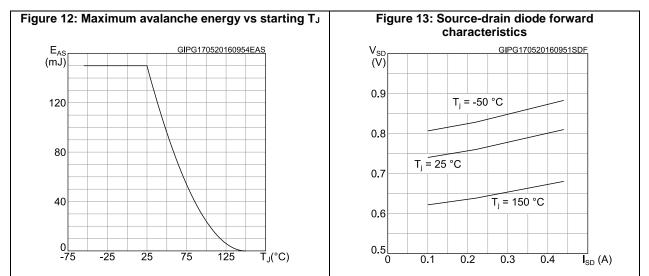
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Electrical characteristics

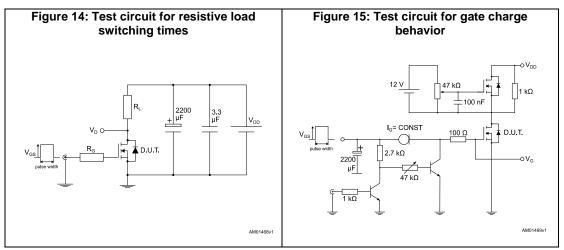


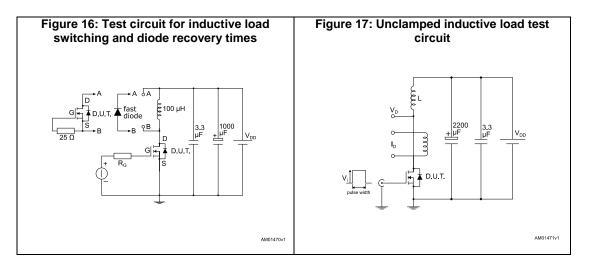


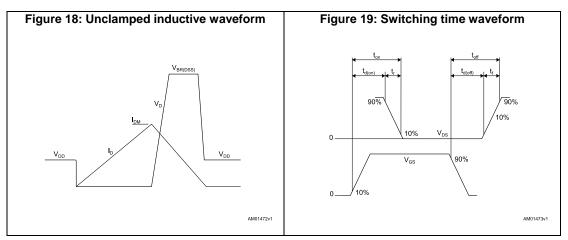


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3 Test circuits





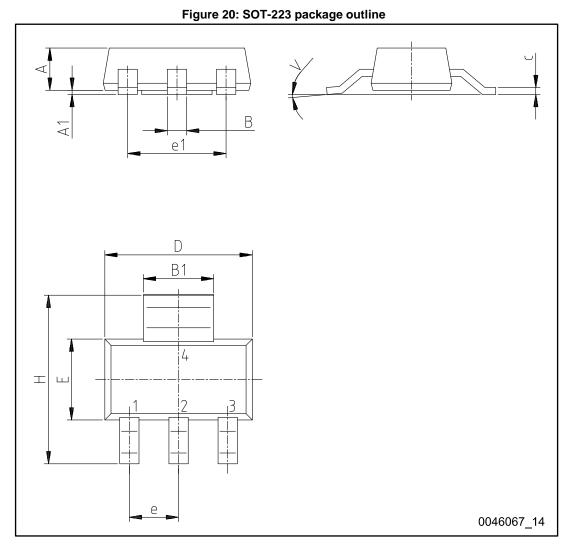




4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

4.1 SOT-223 package information



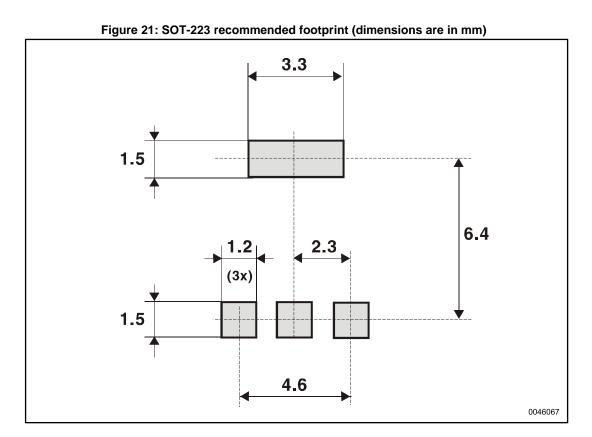


Package information

Table 9: SOT-223 package mechanical data

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Table 9: 501-223 package mechanical data			
Dim.		mm	
Dini.	Min.	Тур.	Max.
A			1.8
A1	0.02		0.1
В	0.6	0.7	0.85
B1	2.9	3	3.15
С	0.24	0.26	0.35
D	6.3	6.5	6.7
е		2.3	
e1		4.6	
E	3.3	3.5	3.7
Н	6.7	7.0	7.3
V			10°



5 Revision history

Table 10: Document revision history

Date	Revision	Changes
12-Nov-2015	1	First release.
05-Dec-2016	2	Modified: features in cover page Modified Table 2: "Absolute maximum ratings", Table 3: "Thermal data", Table 4: "Avalanche characteristics", Table 5: "On/off-state", Table 6: "Dynamic", Table 7: "Switching times" and Table 8: "Source- drain diode" Datasheet promoted from preliminary data to production data Modified Section 3.1: "Electrical characteristics (curves)" Minor text changes



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